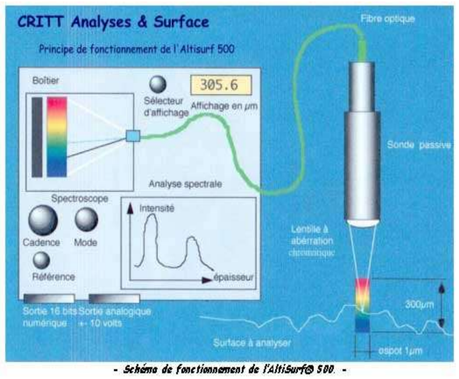
PROFILOMETER - Equipment

Surface, **linear** or **static** topography measures
CONTACTLESS from ambiant to **300°C**
Source of light = beam white light

2 probes : 300 µm
3 mm **only probe used in T°C**

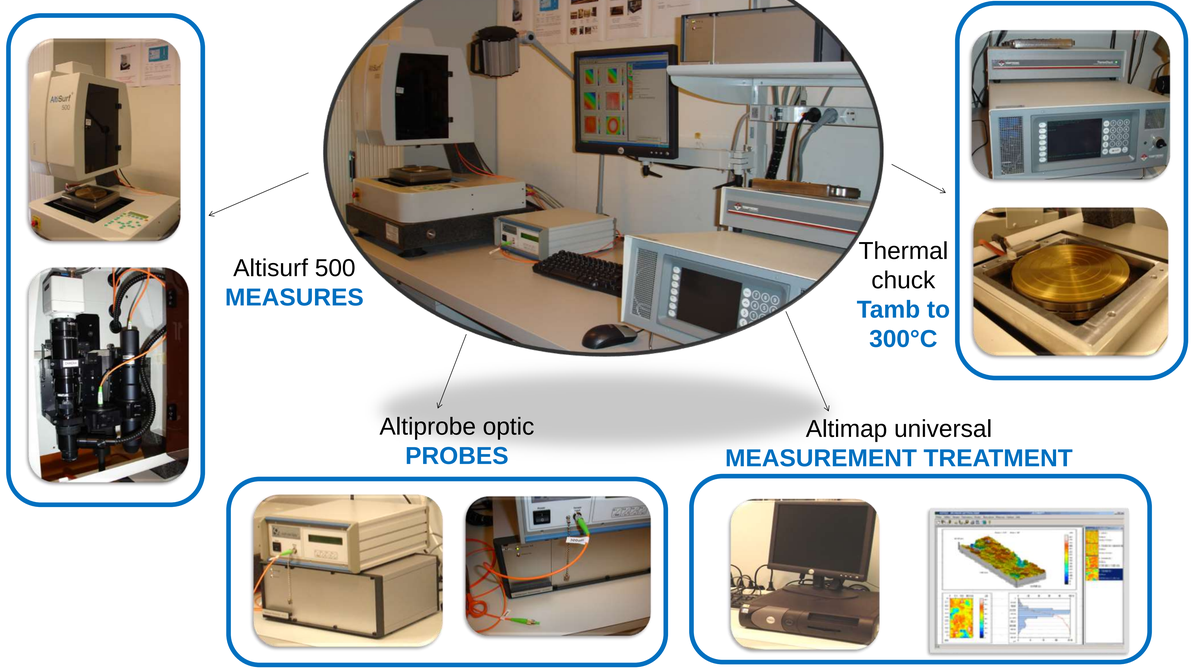
A beam of light resulting from a halogenous lamp (white, polychromatic light) goes through a fiberoptic to a passive probe which has a lens with strong chromatic aberration. The beam of light is splitted into wavelengths monochromatic on the distance from the range of measurement (300 µm or 3mm).



- Schéma de fonctionnement de l'AltiSurf® 500. -

Measurement bracket	Vertical Resolution	Work distance	Spot diameter	Measure frequency
0 – 300 µm 0 – 3 mm	10 nm 100 nm	4.5 mm 38 mm	1 µm 25 µm	30 à 1000 Hz maxi

According to the relief of analyzed surface, certain monochromatic wavelengths will be considered. Those wavelengths will be interpreted in term of altitude.



Altisurf 500
MEASURES

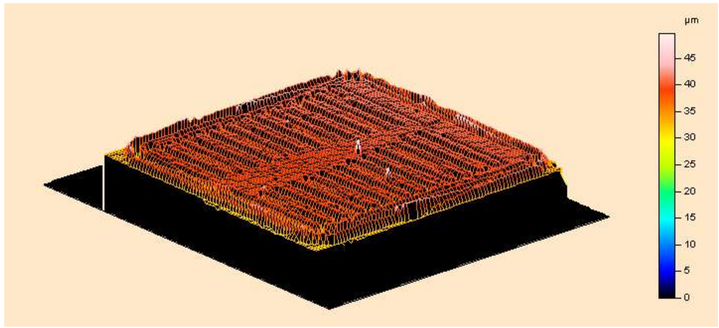
Thermal chuck
Tamb to 300°C

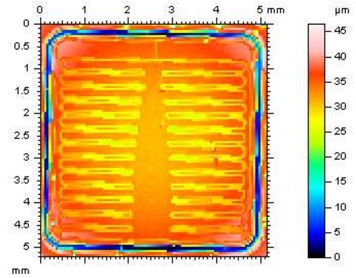
Altiprobe optic
PROBES

Altimap universal
MEASUREMENT TREATMENT

PROFILOMETER - Analysis

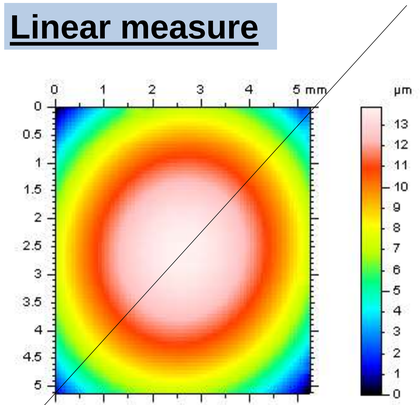
Surface measure

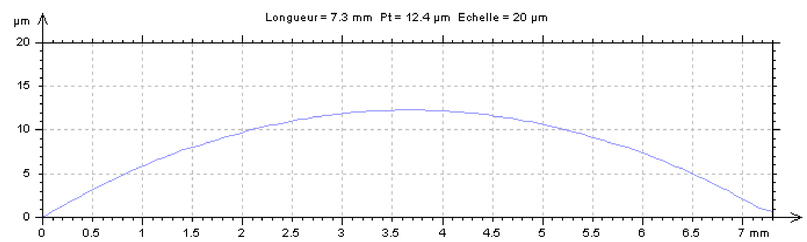




Views of a surface of a BJT (Bipolar Junction Transistor) – BUX 48

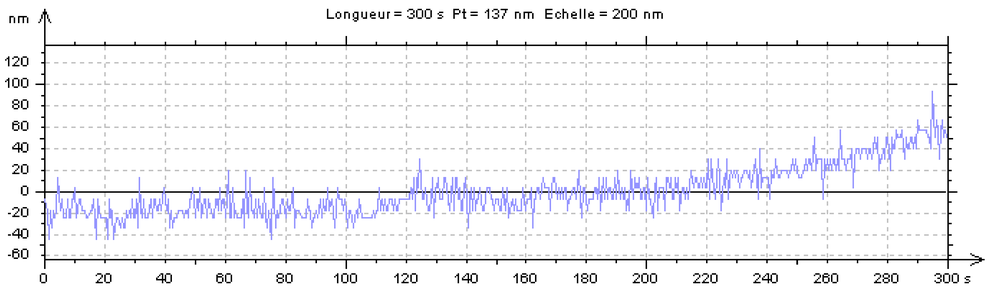
Linear measure





Profile extracted from a surface

Static measure



Static evolution of the middle point of a die after refusion